# Photolithography Mask Design

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# Background: EE432/532

- EE 432/532 is a microelectronics fabrication class
  Popular class
- Make a silicon wafer with devices including MOSFET and BJT
  - in an educational purpose class
- A hands on class with lab at Applied Science Complex
  - Diffusion
  - Oxidation
  - Photolithography
    - mask
  - Evaporation
  - And more

# Photolithography

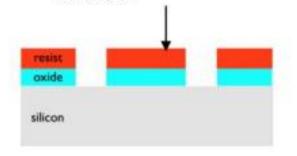


Exposure of UV light to photoresist with mask



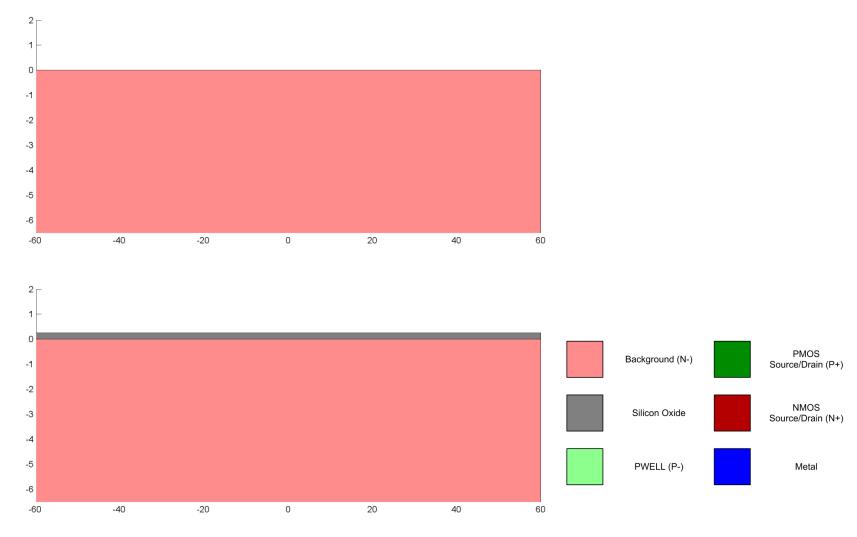
Photoresist is washed away using acetone

Removal of exposed photoresist by developer

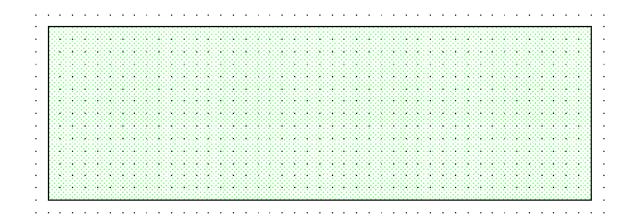


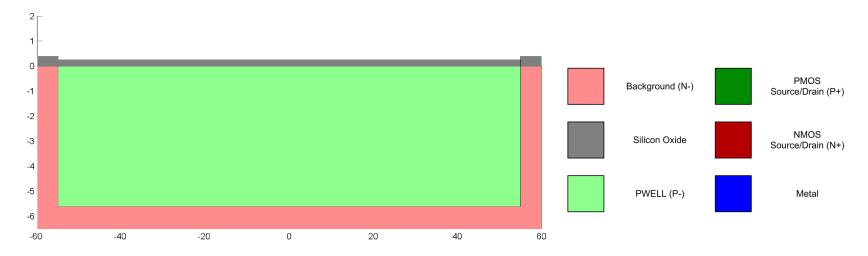
#### Removal of oxide in exposed regions

#### Bare Wafer

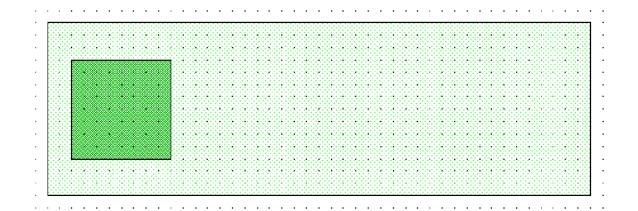


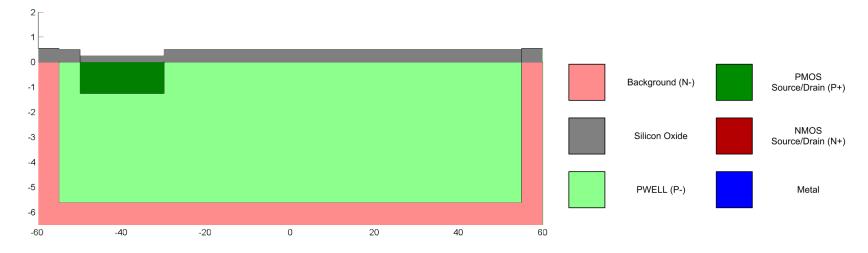
#### Pattern PWELL



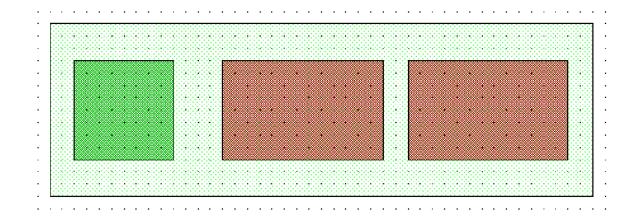


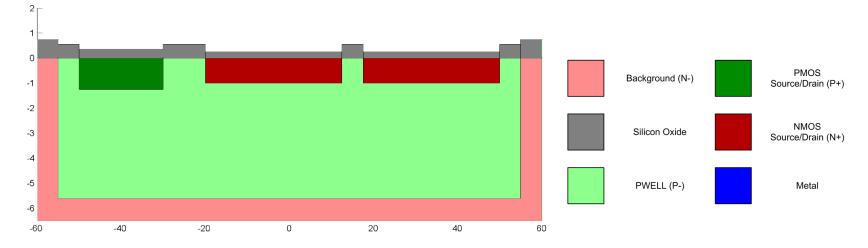
#### Pattern PMOS Source/Drain



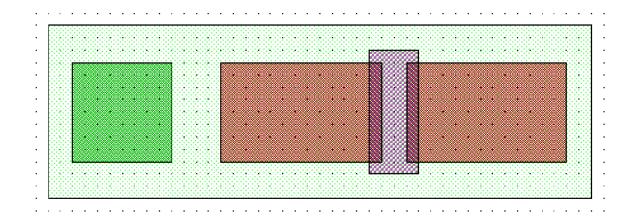


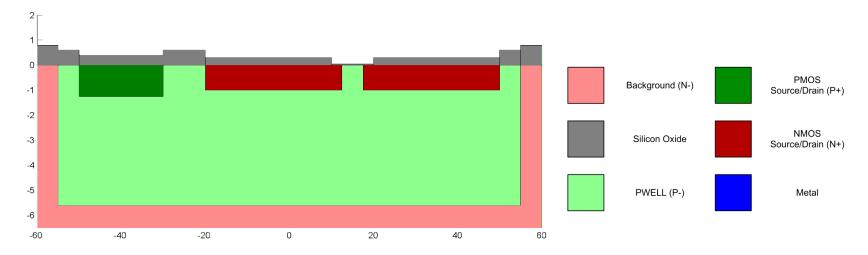
#### Pattern NMOS Source/Drain



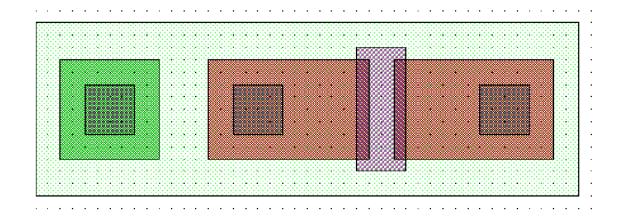


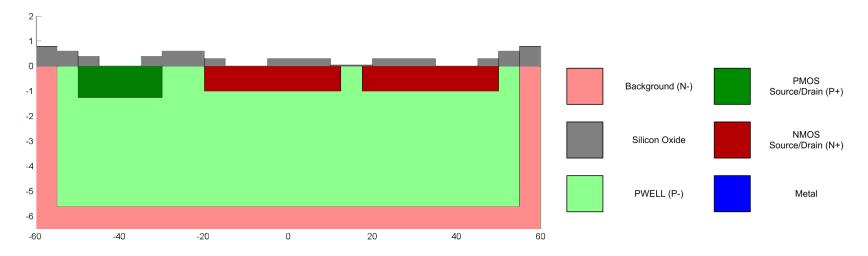
#### Pattern Gate Area



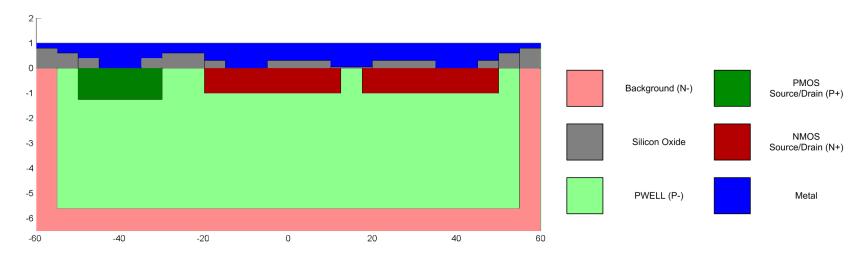


#### Pattern Contacts

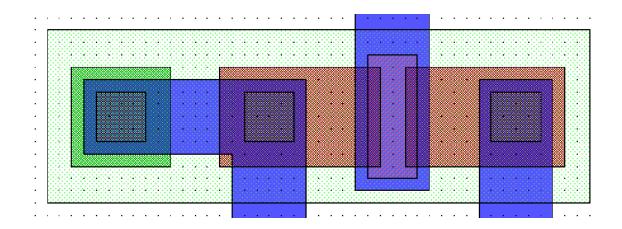


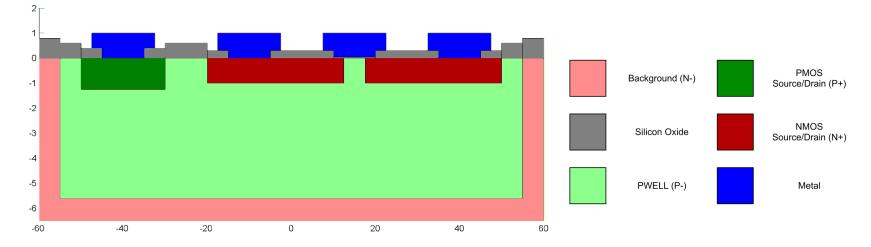


#### Apply Metal to Entire Wafer



#### Pattern Metal





#### **Problem Statement**

- No transistors functioned from the summer 2012 EE 432/532 class
- Problem with old photolithography masks
  - Devices are too small and too close together
  - Mask alignment marks are small and hard to find
  - Wafer space not utilized

#### Scope

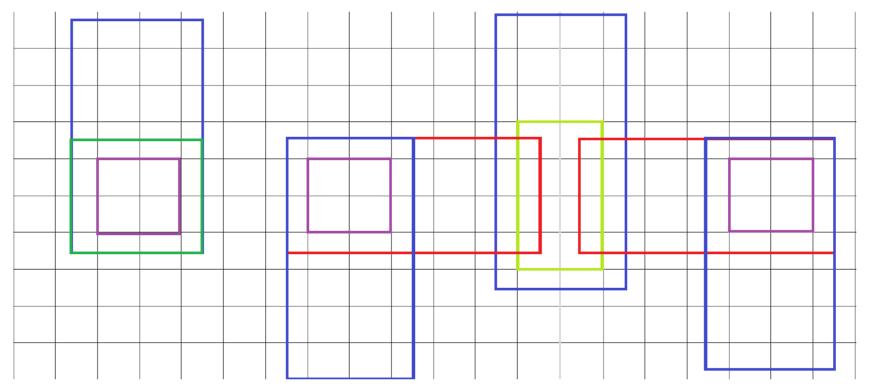
- Design a set of photolithography masks (six) that can be used in the EE 432 lab
- The EE 432 process outside of the masks stays the same
- Use L-Edit (CAD tool) to design the masks

#### Deliverables

- A set of six photolithography masks
- Mask documentation for student use
- A set of fabricated wafers to test

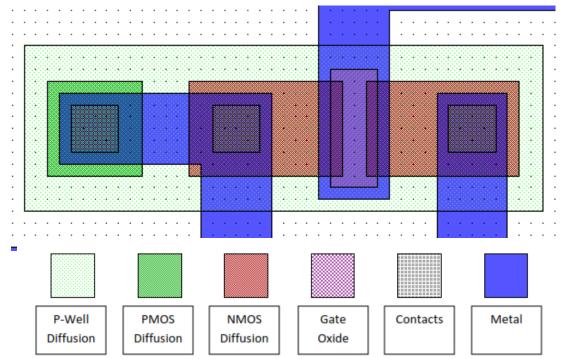
# Initial Design

• Rough sketch of transistor

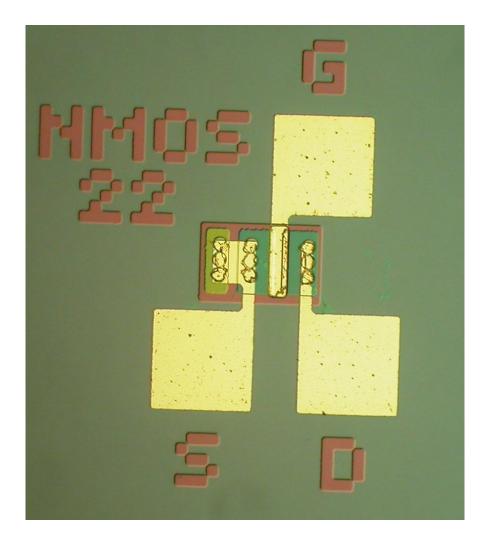


# L-Edit Design

- Current Actual transistor design
- Each dot represents 2.5um

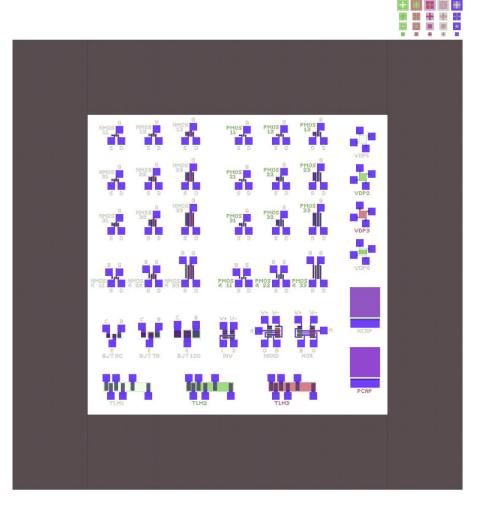


#### **Fabricated Transistor**

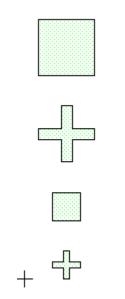


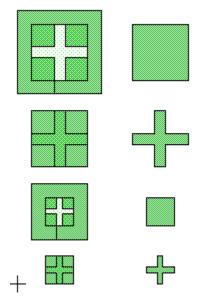
# Die Design

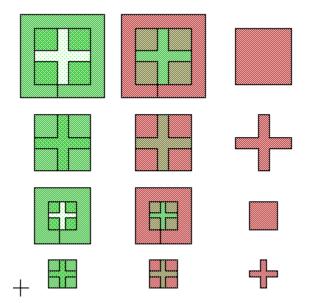
- One die (a set of transistor, e.g. a Intel CPU core)
- 39 devices per die
- 9 different devices per die
- Devices includes MOSFET, BJT, VDP, capacitors, TLM(resistor), and logic gates

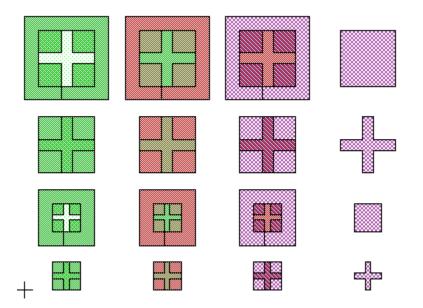


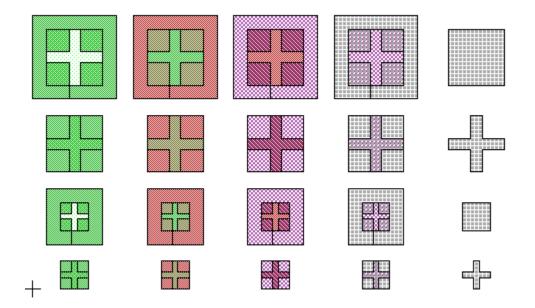
#### **Alignment Marks**

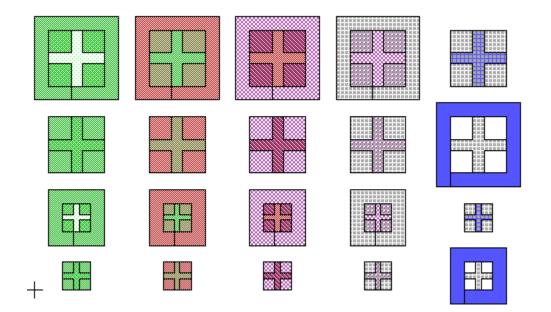




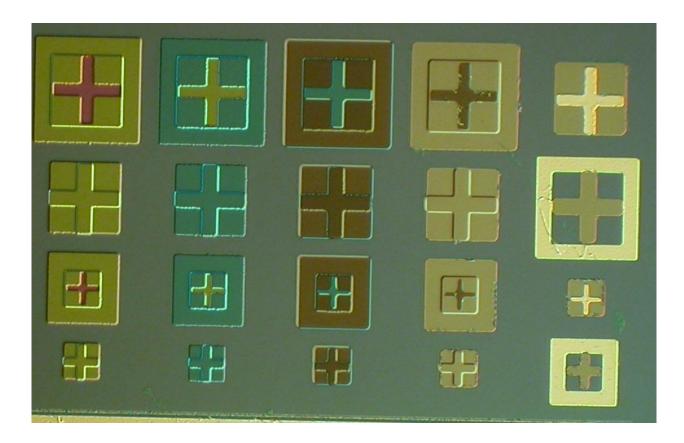




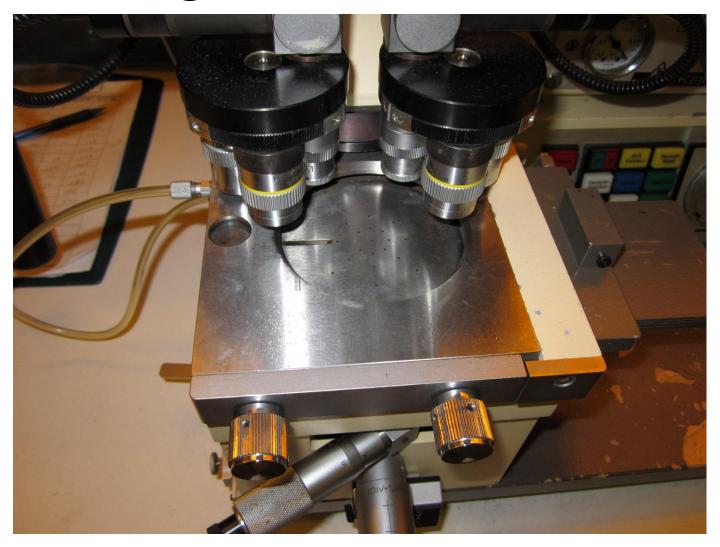




#### Fabricated Alignment Marks

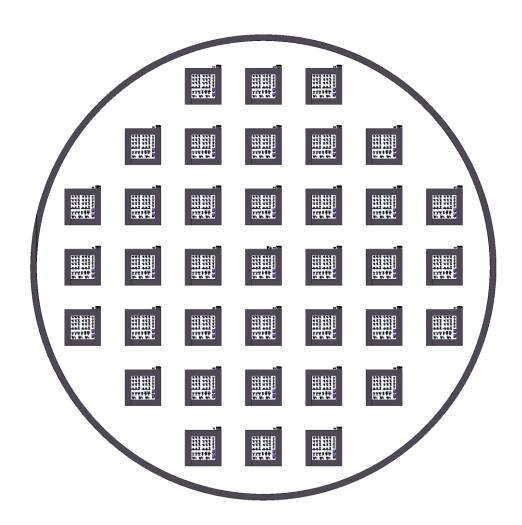


#### **Alignment Machine**



# Mask Design

- The entire mask has 37 die
- A ring around all the dies
  - Helps align the mask with the alignment machine.



# Challenges

- Problem: The masks cannot be tested before fabrication
- Solution: Spending extra time in the design phase working on analysis. We got each design approved by our advisor before getting any masks fabricated

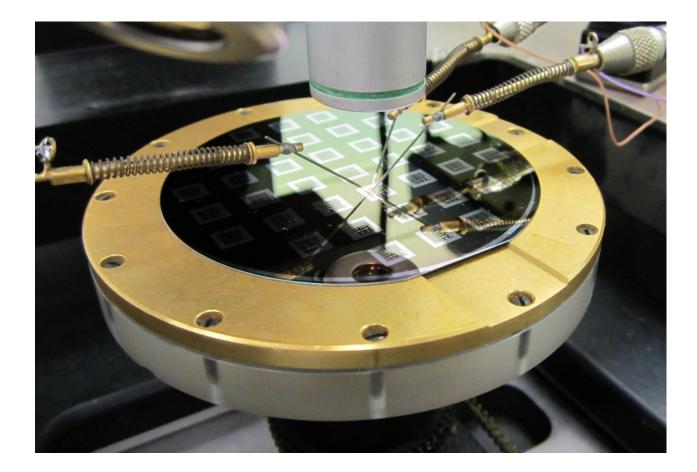
# Challenges

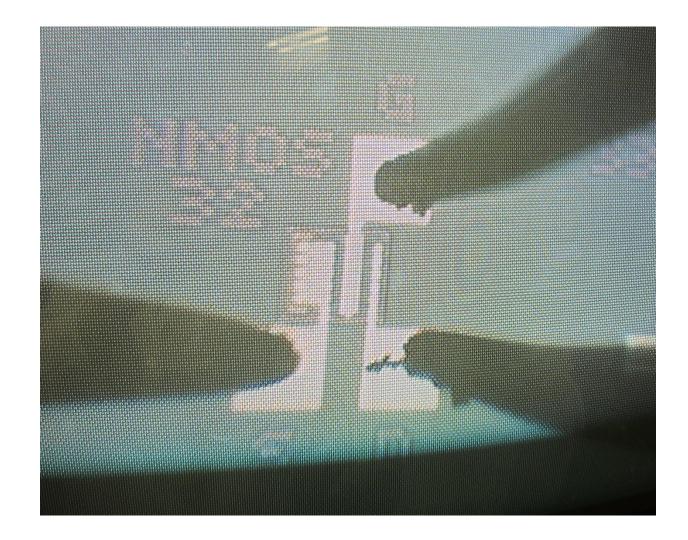
- Problem: Developing a set of design rules for the devices
- Solution: We spent time looking at the old design, and looked for areas where they may not have left enough spacing. We met with our advisor to approve all design rules.

# Challenges

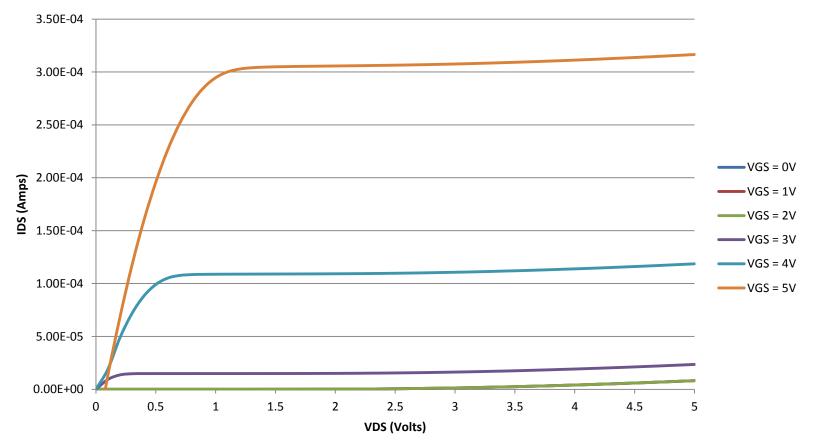
- Problem: Working with new software (L-Edit)
- Solution: Used our experience with similar software (Cadence). We spent some time going through the L-Edit documentation to better use the software features.

- A set of wafers have been fabricated using the new mask set
  - Alignment successful
  - Functional transistors
  - More space utilized



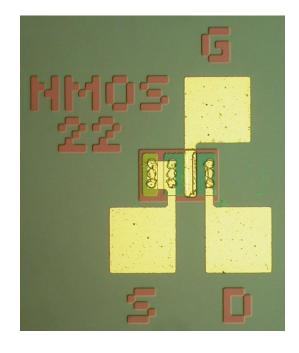






#### What Worked

- All groups had working NMOS transistors
- Most NMOS transistors worked except for the smallest (5 micron length)
- Over half the groups had working PMOS transistors



#### **Transistor Results**

- NMOS
  - Threshold voltage ranged from 2.4 to 2.9 volts
- PMOS
  - Threshold voltage ranged from -1.4 to -1.7 volts
- TLM Pattern
  - Showed contacts where ohmic with V=IR relationship

#### Questions?

